Noninverting 3-State Buffer

The MC74VHC1G126 is an advanced high speed CMOS noninverting 3-state buffer fabricated with silicon gate CMOS technology. It achieves high speed operation similar to equivalent Bipolar Schottky TTL while maintaining CMOS low power dissipation.

The internal circuit is composed of three stages, including a buffered 3–state output which provides high noise immunity and stable output.

The MC74VHC1G126 input structure provides protection when voltages up to 7.0 V are applied, regardless of the supply voltage. This allows the MC74VHC1G126 to be used to interface 5.0 V circuits to 3.0 V circuits.

- High Speed: $t_{PD} = 3.5 \text{ ns}$ (Typ) at $V_{CC} = 5.0 \text{ V}$
- Low Power Dissipation: $I_{CC} = 1 \mu A \text{ (Max)}$ at $T_A = 25 \text{°C}$
- Power Down Protection Provided on Inputs
- Balanced Propagation Delays
- Pin and Function Compatible with Other Standard Logic Families
- Chip Complexity: FETs = 58; Equivalent Gates = 15

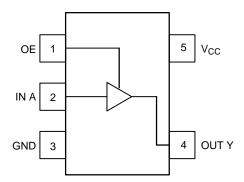


Figure 1. Pinout (Top View)

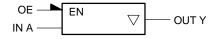


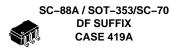
Figure 2. Logic Symbol



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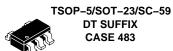
http://onsemi.com

MARKING DIAGRAMS





Pin 1 d = Date Code





Pin 1 d = Date Code

PIN ASSIGNMENT						
1	OE					
2	IN A					
3	GND					
4	OUT Y					
5	V _{CC}					

FUNCTION TABLE

A Input	OE Input	Y Output
L	Н	L
Н	Н	Н
X	L	z

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 4 of this data sheet.

MAXIMUM RATINGS (Note 1)

Symbol	Characteristics		Value	Unit
V _{CC}	DC Supply Voltage		-0.5 to +7.0	V
V _{IN}	DC Input Voltage		-0.5 to +7.0	V
V _{OUT}	DC Output Voltage	V _{CC} = 0 or Low State	-0.5 to 7.0 -0.5 to V _{CC} + 0.5	V
I _{IK}	Input Diode Current		-20	mA
lok	Output Diode Current V _{OUT} < GND;	V _{OUT} > V _{CC}	+20	mA
I _{OUT}	DC Output Current, per Pin		+25	mA
Icc	DC Supply Current, V _{CC} and GND		+50	mA
P _D	Power dissipation in still air SC–88A,	TSOP-5	200	mW
θ_{JA}	Thermal resistance SC-88A,	TSOP-5	333	°C/W
T _L	Lead temperature, 1 mm from case for 10 s		260	°C
TJ	Junction temperature under bias		+150	°C
T _{stg}	Storage temperature		-65 to +150	°C
V _{ESD}	ESD Withstand Voltage Human Body Mo Machine Mo Charged Device Mo	odel (Note 3)	> 2000 > 200 N/A	V
I _{Latch-Up}	Latch–Up Performance Above V _{CC} and Below GND at 12	5°C (Note 5)	±500	mA

Maximum Ratings are those values beyond which damage to the device may occur. Exposure to these conditions or conditions beyond those
indicated may adversely affect device reliability. Functional operation under absolute-maximum-rated conditions is not implied. Functional
operation should be restricted to the Recommended Operating Conditions.

- 2. Tested to EIA/JESD22-A114-A
- 3. Tested to EIA/JESD22-A115-A
- 4. Tested to JESD22-C101-A
- 5. Tested to EIA/JESD78

RECOMMENDED OPERATING CONDITIONS

Symbol	Characteristics	Min	Max	Unit	
V _{CC}	DC Supply Voltage	2.0	5.5	V	
V _{IN}	DC Input Voltage	0.0	5.5	V	
V _{OUT}	DC Output Voltage		0.0	V _{CC}	V
T _A	Operating Temperature Range		-55	+125	°C
t _r , t _f	Input Rise and Fall Time	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$ $V_{CC} = 5.0 \text{ V} \pm 0.5 \text{ V}$	0	100 20	ns/V

Device Junction Temperature versus Time to 0.1% Bond Failures

Junction Temperature °C	Time, Hours	Time, Years
80	1,032,200	117.8
90	419,300	47.9
100	178,700	20.4
110	79,600	9.4
120	37,000	4.2
130	17,800	2.0
140	8,900	1.0

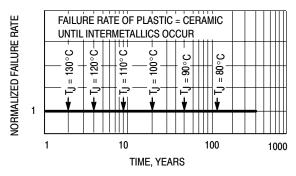


Figure 3. Failure Rate vs. Time Junction Temperature

DC ELECTRICAL CHARACTERISTICS

			v _{cc}	1	_A = 25°(С	T _A ≤	85°C	-55 ≤ T _A	≤ 125°C	
Symbol	Parameter	Test Conditions	(V)	Min	Тур	Max	Min	Max	Min	Max	Unit
V _{IH}	Minimum High-Level Input Voltage		2.0 3.0 4.5 5.5	1.5 2.1 3.15 3.85			1.5 2.1 3.15 3.85		1.5 2.1 3.15 3.85		٧
V _{IL}	Maximum Low–Level Input Voltage		2.0 3.0 4.5 5.5			0.5 0.9 1.35 1.65		0.5 0.9 1.35 1.65		0.5 0.9 1.35 1.65	V
V _{OH}	Minimum High–Level Output Voltage V _{IN} = V _{IH} or V _{IL}	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OH} = -50 \mu\text{A}$	2.0 3.0 4.5	1.9 2.9 4.4	2.0 3.0 4.5		1.9 2.9 4.4		1.9 2.9 4.4		V
		$V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OH} = -4 \text{ mA}$ $I_{OH} = -8 \text{ mA}$	3.0 4.5	2.58 3.94			2.48 3.80		2.34 3.66		V
V _{OL}	Maximum Low–Level Output Voltage V _{IN} = V _{IH} or V _{IL}	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OL} = 50 \mu\text{A}$	2.0 3.0 4.5		0.0 0.0 0.0	0.1 0.1 0.1		0.1 0.1 0.1		0.1 0.1 0.1	V
		$V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OL} = 4 \text{ mA}$ $I_{OL} = 8 \text{ mA}$	3.0 4.5			0.36 0.36		0.44 0.44		0.52 0.52	V
I _{OZ}	Maximum 3–State Leakage Current	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$	5.5			±0.25		±2.5		±2.5	μΑ
I _{IN}	Maximum Input Leakage Current	V _{IN} = 5.5 V or GND	0 to 5.5			±0.1		±1.0		±1.0	μΑ
I _{CC}	Maximum Quiescent Supply Current	$V_{IN} = V_{CC}$ or GND	5.5			1.0		20		40	μΑ

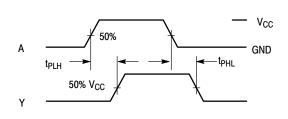
AC ELECTRICAL CHARACTERISTICS C_{load} = 50 pF, Input t_{r} = t_{f} = 3.0 ns

			1	T _A = 25°(3	$T_A \le 85^{\circ}C$		$-55 \le T_A \le 125$ °C		
Symbol	Parameter	Test Conditions	Min	Тур	Max	Min	Max	Min	Max	Unit
t _{PLH} , t _{PHL}	Maximum Propagation Delay,	$V_{CC} = 3.3 \pm 0.3 \text{ V C}_{L} = 15 \text{ pF}$ $C_{L} = 50 \text{ pF}$		4.5 6.4	8.0 11.5		9.5 13.0		12.0 16.0	ns
	Input A to Y (Figures 3. and 5.)	$V_{CC} = 5.0 \pm 0.5 \text{ V } C_L = 15 \text{ pF} $ $C_L = 50 \text{ pF} $		3.5 4.5	5.5 7.5		6.5 8.5		8.5 10.5	
t _{PZL} , t _{PZH}	Maximum Output Enable Time,	$\begin{array}{c} \text{V}_{\text{CC}} = 3.3 \pm 0.3 \; \text{V} \; \text{C}_{\text{L}} = 15 \; \text{pF} \\ \text{R}_{\text{L}} = 1000 \; \Omega \qquad \qquad \text{C}_{\text{L}} = 50 \; \text{pF} \end{array}$		4.5 6.4	8.0 11.5		9.5 13.0		11.5 15.0	ns
	Input OE to Y (Figures 4. and 5.)	$\begin{array}{c} \text{V}_{\text{CC}} = 5.0 \pm 0.5 \; \text{V} \; \text{C}_{\text{L}} = 15 \; \text{pF} \\ \text{R}_{\text{L}} = 1000 \; \Omega \qquad \qquad \text{C}_{\text{L}} = 50 \; \text{pF} \end{array}$		3.5 4.5	5.1 7.1		6.0 8.0		8.5 10.5	
t _{PLZ} , t _{PHZ}	Maximum Output Disable Time,	$\begin{array}{c} \text{V}_{\text{CC}} = 3.3 \pm 0.3 \; \text{V} \; \text{C}_{\text{L}} = 15 \; \text{pF} \\ \text{R}_{\text{L}} = 1000 \; \Omega \qquad \qquad \text{C}_{\text{L}} = 50 \; \text{pF} \end{array}$		6.5 8.0	9.7 13.2		11.5 15.0		14.5 18.0	ns
	Input OE to Y (Figures 4. and 5.)	$\begin{aligned} & \text{V}_{\text{CC}} = 5.0 \pm 0.5 \; \text{V} \; \text{C}_{\text{L}} = 15 \; \text{pF} \\ & \text{R}_{\text{L}} = 1000 \; \Omega \qquad \qquad \text{C}_{\text{L}} = 50 \; \text{pF} \end{aligned}$		4.8 7.0	6.8 8.8		8.0 10.0		10.0 12.0	
C _{IN}	Maximum Input Capacitance			4.0	10		10		10	pF
C _{OUT}	Maximum 3–State Output Capacitance (Output in High Impedance State)			6.0						pF

		Typical @ 25°C, V _{CC} = 5.0 V	
C _{PD}	Power Dissipation Capacitance (Note 6)	8.0	pF

^{6.} C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation: I_{CC(OPR)} = C_{PD} • V_{CC} • f_{in} + I_{CC}. C_{PD} is used to determine the no–load dynamic power consumption; P_D = C_{PD} • V_{CC}² • f_{in} + I_{CC} • V_{CC}.

SWITCHING WAVEFORMS



V_{CC}

GND

TPZL TPLZ

HIGH
IMPEDANCE

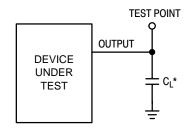
V_{OL} + 0.3V

VOH - 0.3V

HIGH
IMPEDANCE

Figure 4. Switching Waveforms

Figure 5.



*Includes all probe and jig capacitance

DEVICE UNDER TEST C_L^* CONNECT TO V_{CC} WHEN TESTING t_{PLZ} AND t_{PZL} CONNECT TO GND WHEN TESTING t_{PHZ} AND t_{PZH} .

*Includes all probe and jig capacitance

Figure 6. Test Circuit

Figure 7. Test Circuit

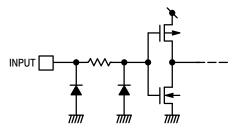


Figure 8. Input Equivalent Circuit

DEVICE ORDERING INFORMATION

	Device Nomenclature							
Device Order Number	Circuit Indicator	Temp Range Identifier	Technology	Device Function	Package Suffix	Tape & Reel Suffix	Package Type (Name/SOT#/ Common Name)	Tape and Reel Size [†]
MC74VHC1G126DFT1	МС	74	VHC1G	126	DF	T1	SC-88A / SOT-353 / SC-70	178 mm (7") 3000 Unit
MC74VHC1G126DFT2	МС	74	VHC1G	126	DF	T2	SC-88A / SOT-353 / SC-70	178 mm (7") 3000 Unit
MC74VHC1G126DTT1	MC	74	VHC1G	126	DT	T1	TSOP-5 / SOT-23 / SC-59	178 mm (7") 3000 Unit

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

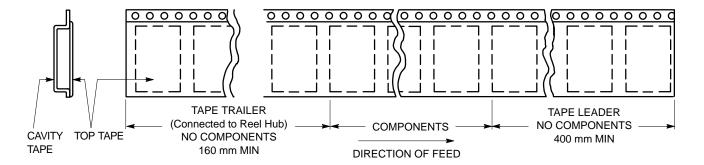


Figure 9. Tape Ends for Finished Goods

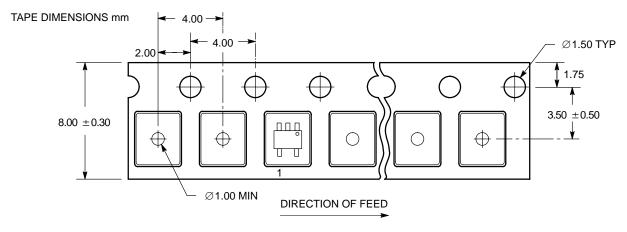


Figure 10. SC-70-5/SC-88A/SOT-353 DFT1 Reel Configuration/Orientation

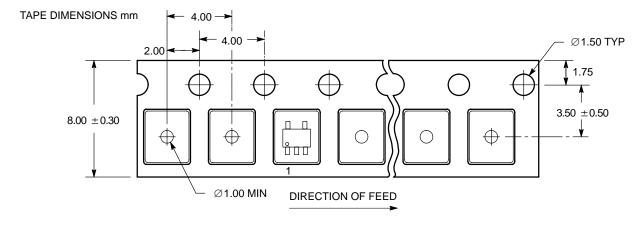


Figure 11. SC-70/SC-88A/SOT-353 DFT2 and SOT23-5/TSOP-5/SC59-5 DTT1 Reel Configuration/Orientation

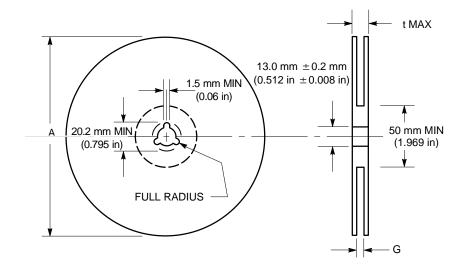


Figure 12. Reel Dimensions

REEL DIMENSIONS

Tape Size	T and R Suffix	A Max	G	t Max
8 mm	T1, T2	178 mm (7 in)	8.4 mm, + 1.5 mm, -0.0 (0.33 in + 0.059 in, -0.00)	14.4 mm (0.56 in)

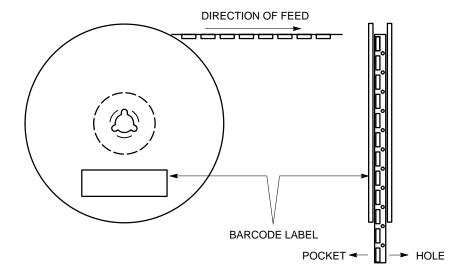
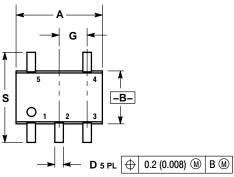


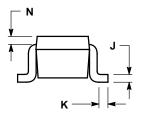
Figure 13. Reel Winding Direction

PACKAGE DIMENSIONS

SC70-5/SC-88A/SOT-353 **DF SUFFIX**

5-LEAD PACKAGE CASE 419A-02 ISSUE G





- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.
 3. 419A-01 OBSOLETE. NEW STANDARD
- 419A-02.
 DIMENSIONS A AND B DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

	INC	HES	MILLIM	ETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.071	0.087	1.80	2.20	
В	0.045	0.053	1.15	1.35	
С	0.031	0.043	0.80	1.10	
D	0.004	0.012	0.10	0.30	
G	0.026	BSC	0.65 BSC		
Н		0.004		0.10	
J	0.004	0.010	0.10	0.25	
K	0.004	0.012	0.10	0.30	
N	0.008	0.008 REF		REF	
S	0.079	0.087	2.00	2.20	

SOLDERING FOOTPRINT*

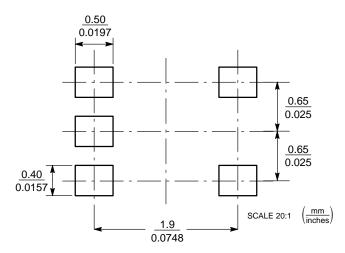


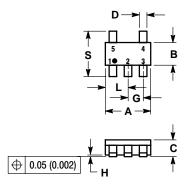
Figure 14. SC-88A/SC70-5/SOT-353

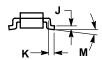
^{*}For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

SOT23-5/TSOP-5/SC59-5 **DT SUFFIX**

5-LEAD PACKAGE CASE 483-01 ISSUE C





NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- ANSI 114-3M, 1992.
 CONTROLLING DIMENSION: MILLIMETER.
 MAXIMUM LEAD THICKNESS INCLUDES
 LEAD FINISH THICKNESS. MINIMUM LEAD
 THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL.
- A AND B DIMENSIONS DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE

	MILLIN	IETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	2.90	3.10	0.1142	0.1220
В	1.30	1.70	0.0512	0.0669
С	0.90	1.10	0.0354	0.0433
D	0.25	0.50	0.0098	0.0197
G	0.85	1.05	0.0335	0.0413
Н	0.013	0.100	0.0005	0.0040
J	0.10	0.26	0.0040	0.0102
K	0.20	0.60	0.0079	0.0236
L	1.25	1.55	0.0493	0.0610
М	0	10	0	10
S	2.50	3.00	0.0985	0.1181

SOLDERING FOOTPRINT*

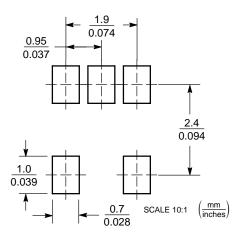


Figure 15. THIN SOT23-5/TSOP-5/SC59-5

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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